

**Preliminary Amendment**

Applicant: Claus Dworski et al.

Serial No.: Unknown

(Priority Application No. 103 32 008.3)

(International Application No. PCT/DE2004/001148)

Filed: Herewith

(Priority Date 14 July 2003)

(International Filing Date 04 June 2004)

Docket No. I431.144.101/FIN 503 PCT/US

Title: ELECTRICAL CIRCUIT AND METHOD FOR TESTING ELECTRONIC COMPONENT

---

**IN THE ABSTRACT**

Please replace the Abstract with the following rewritten paragraph:

Abstract

**ELECTRICAL CIRCUIT AND METHOD FOR TESTING INTEGRATED CIRCUITS**

**Abstract**

An electrical test circuit is disclosed. In one embodiment, The electrical test circuit ~~(5) comprises~~includes a first input ~~(51)~~ for receiving a test signal of an integrated circuit ~~(4)~~, a second input ~~(52)~~ for receiving a control signal and a third input ~~(53)~~ for receiving a normalized reference signal, particularly one that is formed to be synchronous with the test signal. Using a control device ~~(55)~~ of the electrical test circuit ~~(5)~~, the deviation and/or the amplitude and/or the phase of the reference signal and/or of the test signal can be varied. A measuring device ~~(56)~~ generates, by subtracting the reference signal from the test signal, a difference signal which is output via an output ~~(54)~~.

~~(Fig. 2)~~